



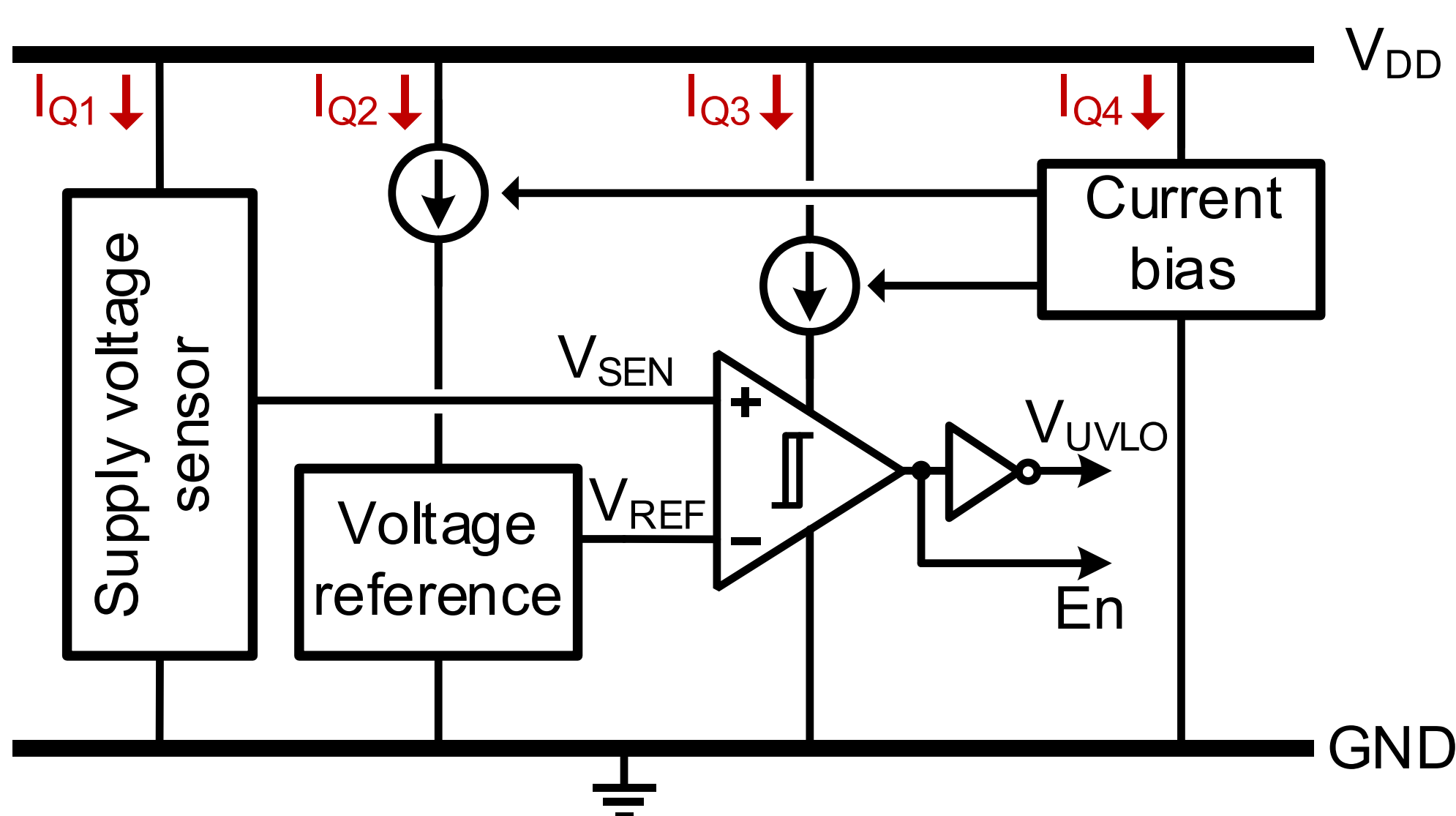
## A 10.9-nA Self-Biased Standalone Under-Voltage Lockout Circuit for Always-On Power Monitoring at 5 V



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### Motivation



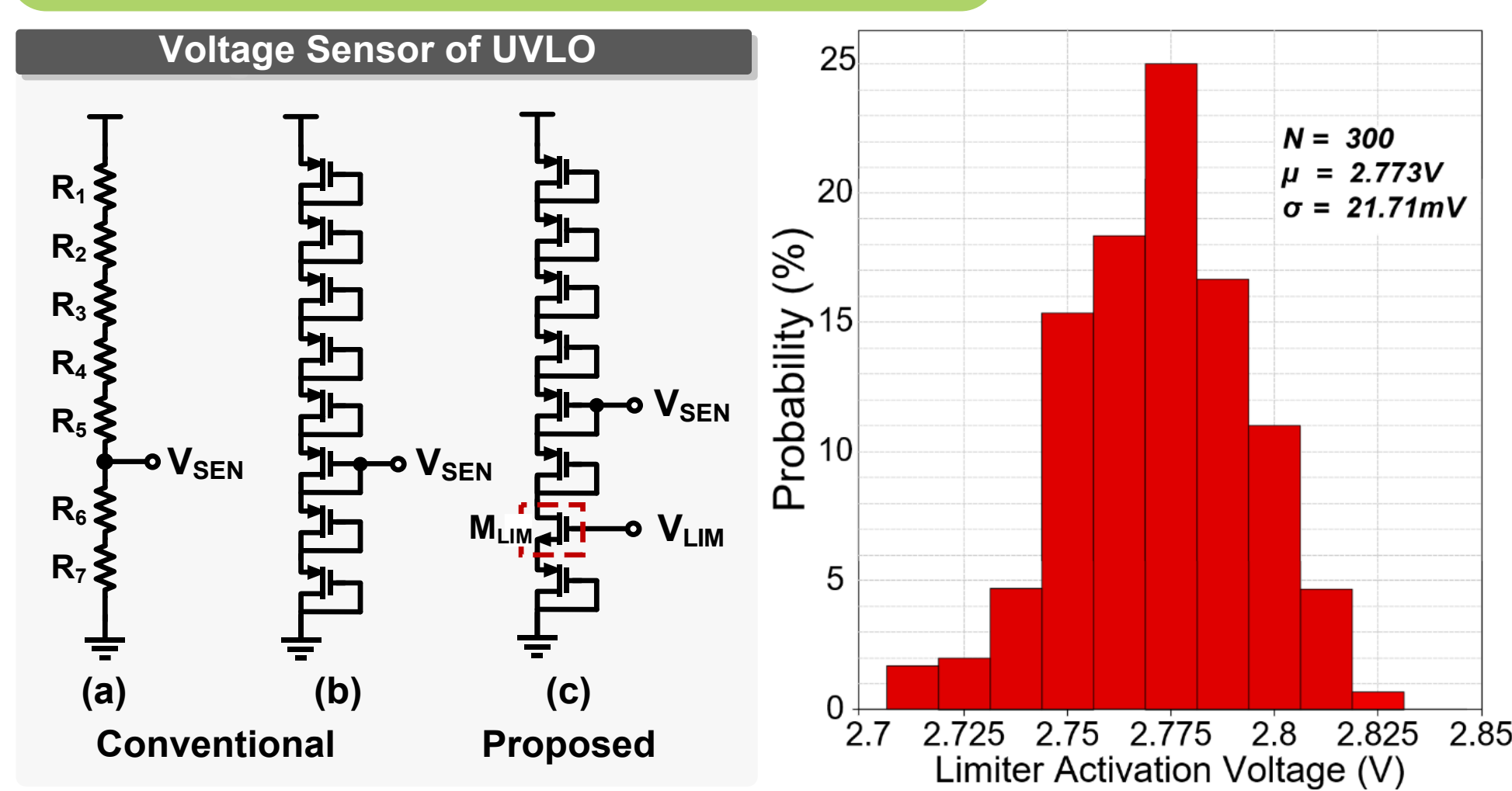
#### ❖ Limitation of Conventional UVLO

- ✓ Continuous static current from the resistive divider and bias circuits
- ✓ Difficulty in achieving nanoampere-level  $I_Q$  for always-on operation
- ✓  $I_Q$  increases with  $V_{DD}$ , degrading standby efficiency

#### ❖ Key Advantages of the Proposed UVLO

- ✓ Self-biased architecture eliminates extra bias circuits
- ✓ MOS-diode divider with current limiter suppresses  $I_Q$  increase
- ✓ Achieves **10.9 nA**  $I_Q$  at 5 V with **862× current reduction**

### Operation



#### ❖ Sensing Voltage $V_{SEN}$

$$V_{SEN} \approx \frac{2}{7} V_{DD}$$

#### ❖ Current limiter turns on when

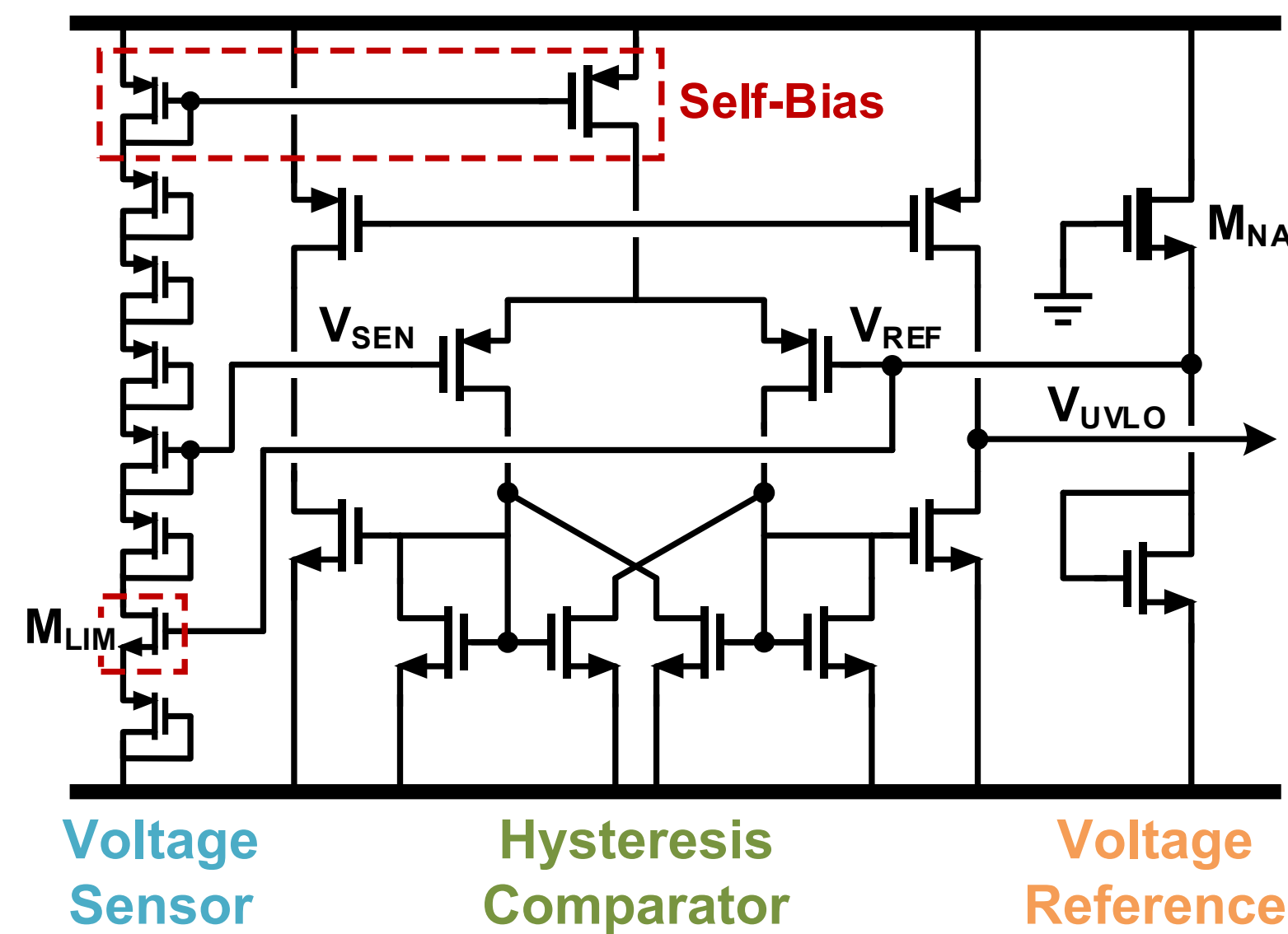
$$V_{SEN} > V_{LIM} + \Delta$$

$$\Delta = V_{SG,M6} - V_{TH,MLIM}$$

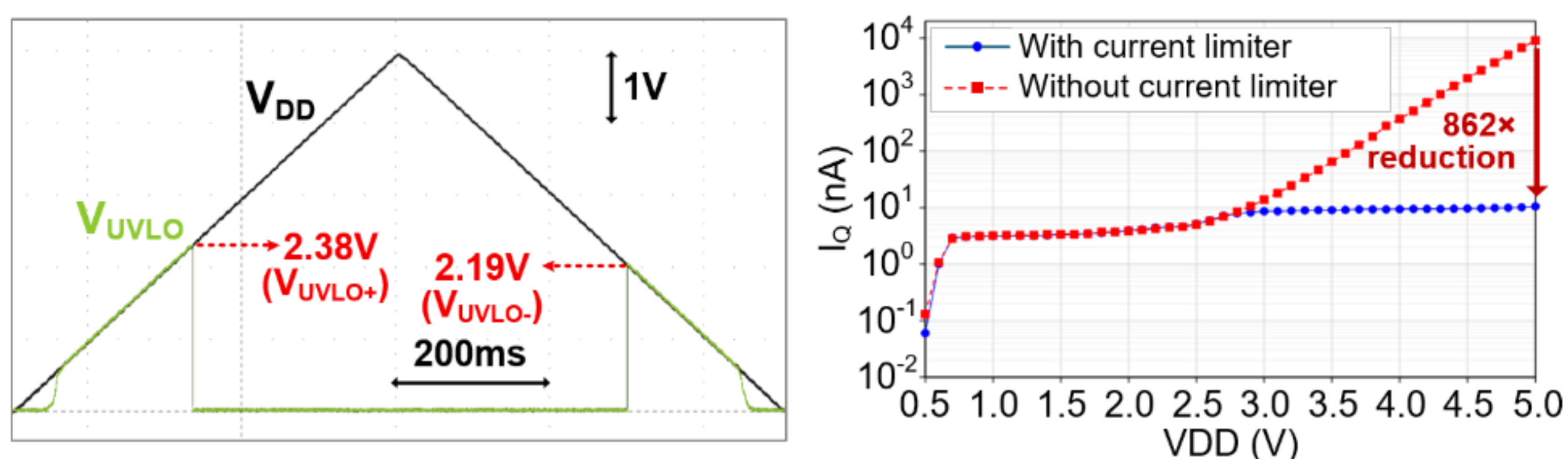
#### ❖ A subthreshold PMOS current mirror provides self-biases for the comparator, eliminating extra bias circuitry

#### ❖ A native-FET-based VREF provides a compact low-current reference

$$V_{REF} \approx 0.65 V$$



### Measurement Results



Parameter	This work	APEC' 17	JSSC' 23	Integration' 23	TI TPS7A02
Process	180 nm CMOS	1.2 μm BCD	500 nm BCD	250 nm BCD	N/A
Quiescent Current @ $V_{DD}$	<b>10.9 nA</b> @ 5 V	27 μA @ 15 V	583 nA @ 12 V	5 μA @ 3.3 V	25 nA @ 5 V
$V_{UVLO+} / V_{UVLO-}$	2.38 V / 2.19 V	1.3 V / 1.12 V	N/A	2.37 V / 1.93 V	8.72 V / 8.24 V
Hysteresis	0.19 V	0.48 V	-	0.44 V	0.18 V
Area	0.014 mm <sup>2</sup>	N/A	0.168 mm <sup>2</sup>	0.226 mm <sup>2</sup>	N/A

#### ❖ Implemented in **180 nm Process**

#### ❖ Achieves ultra-low quiescent current of **10.9 nA** at 5 V

#### ❖ Maintains nearly constant current across a wide $V_{DD}$ range due to the voltage limiter

#### ❖ Demonstrates up to **862×** reduction in current compared to conventional structures

### References

- [1] K. Song, *APEC*, Mar. 2017, pp. 1085–1089 [2] Y. Wen, *JSSC*, Feb. 2023, pp. 497–507  
[3] X. Liu, *JSSC*, Jul. 2024, pp. 2272–2285 [4] Texas Instruments, TPS7A02, Datasheet

### Acknowledgement

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